H.H. Braun, CLIC meeting, 20.2.2004

Permissible Trip Rates for 30 GHz structures in CLIC

- > What is the permissible trip rate as a function of linac energy overhead ?
- > What is the permissible trip rate if break-down affects beam quality?

Permissible Trip Rate as a Function of Linac Energy Overhead

Trip Recovery



This requires that PETS can be switched off from one pulse to next and that field can be ramped with constant phase !

A small fraction R of the total number of installed structures N is reserve. If no structure has tripped they are not fed with power, but decelerate with the beam loaded Voltage V_{B} . They are switched on to compensate the energy loss due to tripped structures.

During the recovery cycle the tripped structures accelerate in average with $oldsymbol{V}$

This implies
$$N_{Trip} < R N \frac{V_A - V_B}{V_A - \overline{V}}$$

If X is the probability that a structure break down in a pulse, we will have in average

$$\left< \boldsymbol{\mathsf{N}_{\mathsf{Trip}}} \right> = \boldsymbol{\mathsf{N}} \; \boldsymbol{\mathsf{M}} \; \boldsymbol{\mathsf{X}} \left(\boldsymbol{\mathsf{T}}_1 + \boldsymbol{\mathsf{T}}_2 \right) \boldsymbol{\mathrm{v}}_{\boldsymbol{\mathsf{REP}}}$$

with **M** the number of structures connected to a PETS. Since N_{Trip} is a random number it will scatter around this value with a standard deviation $N_{Trip}^{\frac{1}{2}}$. Assuming that we want to cope with 6 standard deviations from $\langle N_{Trip} \rangle$ we get the condition

$$\boldsymbol{X} \leq \frac{18 + \boldsymbol{N} \boldsymbol{R} \boldsymbol{H} - 6\sqrt{9 + \boldsymbol{N} \boldsymbol{R} \boldsymbol{H}}}{\boldsymbol{N} \boldsymbol{M} \boldsymbol{v}_{\boldsymbol{R} \boldsymbol{E} \boldsymbol{P}} \left(\boldsymbol{T}_{1} + \boldsymbol{T}_{2}\right)} \quad \text{with} \quad \boldsymbol{H} = \frac{\boldsymbol{V}_{\boldsymbol{A}} - \boldsymbol{V}_{\boldsymbol{B}}}{\boldsymbol{V}_{\boldsymbol{A}} - \boldsymbol{V}}$$

With

L=0.3 m $E_A = 150 \text{ MV/m}$ $E_B = -22 \text{ MV/m}$ *N*=3 TeV/(L E_A)=666666 *M*=4 $T_1 = 20 \text{ s}$ $T_2 = 20 \text{ s}$ *L*=0.3 m $T_2 = 20 \text{ s}$



What is the permissible trip rate if break-down affects beam quality ?

The vertical momentum of the beam electrons have a gaussian distribution with

$$\sqrt{\left\langle \boldsymbol{P_{Y}}^{2} \right\rangle} = \boldsymbol{P_{Z}} \sqrt{\frac{\boldsymbol{\epsilon_{Y}}}{\gamma \ \boldsymbol{\beta_{Y}}}}$$

this r.m.s. value varies along the linac in the range 5-35 keV/c

Each single cell of an accelerating structure increases P_z by 500 keV/c. A change of field direction in a single cell by 2° during a breakdown event is therefore sufficient to bring the beams out of collisions during this pulse.

If a field distortion of this magnitude occurs, the implication is that all machine pulses with a break-down in a single structure are lost for luminosity.

If this is true the permissible breakdown rate for a 1% luminosity loss is

$$\boldsymbol{X} < \frac{1}{100 \, \boldsymbol{N}}$$
 corresponding to a trip rate of < 0.05/h